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### Understanding [Embedded - CPLDs \(Complex Programmable Logic Devices\)](#)

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

### Applications of Embedded - CPLDs

#### Details

Product Status	Active
Programmable Type	In System Programmable
Delay Time tpd(1) Max	7.5 ns
Voltage Supply - Internal	3V ~ 3.6V
Number of Logic Elements/Blocks	4
Number of Macrocells	64
Number of Gates	1250
Number of I/O	68
Operating Temperature	0°C ~ 70°C (TA)
Mounting Type	Surface Mount
Package / Case	100-TQFP
Supplier Device Package	100-TQFP (14x14)
Purchase URL	<a href="https://www.e-xfl.com/pro/item?MUrl=&amp;PartUrl=epm7064aetc100-7">https://www.e-xfl.com/pro/item?MUrl=&amp;PartUrl=epm7064aetc100-7</a>

**Table 1. MAX 7000A Device Features**

Feature	EPM7032AE	EPM7064AE	EPM7128AE	EPM7256AE	EPM7512AE
Usable gates	600	1,250	2,500	5,000	10,000
Macrocells	32	64	128	256	512
Logic array blocks	2	4	8	16	32
Maximum user I/O pins	36	68	100	164	212
$t_{PD}$ (ns)	4.5	4.5	5.0	5.5	7.5
$t_{SU}$ (ns)	2.9	2.8	3.3	3.9	5.6
$t_{FSU}$ (ns)	2.5	2.5	2.5	2.5	3.0
$t_{CO1}$ (ns)	3.0	3.1	3.4	3.5	4.7
$f_{CNT}$ (MHz)	227.3	222.2	192.3	172.4	116.3

## ...and More Features

- 4.5-ns pin-to-pin logic delays with counter frequencies of up to 227.3 MHz
- MultiVolt™ I/O interface enables device core to run at 3.3 V, while I/O pins are compatible with 5.0-V, 3.3-V, and 2.5-V logic levels
- Pin counts ranging from 44 to 256 in a variety of thin quad flat pack (TQFP), plastic quad flat pack (PQFP), ball-grid array (BGA), space-saving FineLine BGA™, and plastic J-lead chip carrier (PLCC) packages
- Supports hot-socketing in MAX 7000AE devices
- Programmable interconnect array (PIA) continuous routing structure for fast, predictable performance
- PCI-compatible
- Bus-friendly architecture, including programmable slew-rate control
- Open-drain output option
- Programmable macrocell registers with individual clear, preset, clock, and clock enable controls
- Programmable power-up states for macrocell registers in MAX 7000AE devices
- Programmable power-saving mode for 50% or greater power reduction in each macrocell
- Configurable expander product-term distribution, allowing up to 32 product terms per macrocell
- Programmable security bit for protection of proprietary designs
- 6 to 10 pin- or logic-driven output enable signals
- Two global clock signals with optional inversion
- Enhanced interconnect resources for improved routability
- Fast input setup times provided by a dedicated path from I/O pin to macrocell registers
- Programmable output slew-rate control
- Programmable ground pins

The MAX 7000A architecture supports 100% transistor-to-transistor logic (TTL) emulation and high-density integration of SSI, MSI, and LSI logic functions. It easily integrates multiple devices including PALs, GALs, and 22V10s devices. MAX 7000A devices are available in a wide range of packages, including PLCC, BGA, FineLine BGA, Ultra FineLine BGA, PQFP, and TQFP packages. See [Table 3](#) and [Table 4](#).

**Table 3. MAX 7000A Maximum User I/O Pins** *Note (1)*

Device	44-Pin PLCC	44-Pin TQFP	49-Pin Ultra FineLine BGA (2)	84-Pin PLCC	100-Pin TQFP	100-Pin FineLine BGA (3)
EPM7032AE	36	36				
EPM7064AE	36	36	41		68	68
EPM7128A				68	84	84
EPM7128AE				68	84	84
EPM7256A					84	
EPM7256AE					84	84
EPM7512AE						

**Table 4. MAX 7000A Maximum User I/O Pins** *Note (1)*

Device	144-Pin TQFP	169-Pin Ultra FineLine BGA (2)	208-Pin PQFP	256-Pin BGA	256-Pin FineLine BGA (3)
EPM7032AE					
EPM7064AE					
EPM7128A	100				100
EPM7128AE	100	100			100
EPM7256A	120		164		164
EPM7256AE	120		164		164
EPM7512AE	120		176	212	212

**Notes to tables:**

- (1) When the IEEE Std. 1149.1 (JTAG) interface is used for in-system programming or boundary-scan testing, four I/O pins become JTAG pins.
- (2) All Ultra FineLine BGA packages are footprint-compatible via the SameFrame™ feature. Therefore, designers can design a board to support a variety of devices, providing a flexible migration path across densities and pin counts. Device migration is fully supported by Altera development tools. See [“SameFrame Pin-Outs” on page 15](#) for more details.
- (3) All FineLine BGA packages are footprint-compatible via the SameFrame feature. Therefore, designers can design a board to support a variety of devices, providing a flexible migration path across densities and pin counts. Device migration is fully supported by Altera development tools. See [“SameFrame Pin-Outs” on page 15](#) for more details.

## Functional Description

The MAX 7000A architecture includes the following elements:

- Logic array blocks (LABs)
- Macrocells
- Expander product terms (shareable and parallel)
- Programmable interconnect array
- I/O control blocks

The MAX 7000A architecture includes four dedicated inputs that can be used as general-purpose inputs or as high-speed, global control signals (clock, clear, and two output enable signals) for each macrocell and I/O pin. [Figure 1](#) shows the architecture of MAX 7000A devices.

## Expander Product Terms

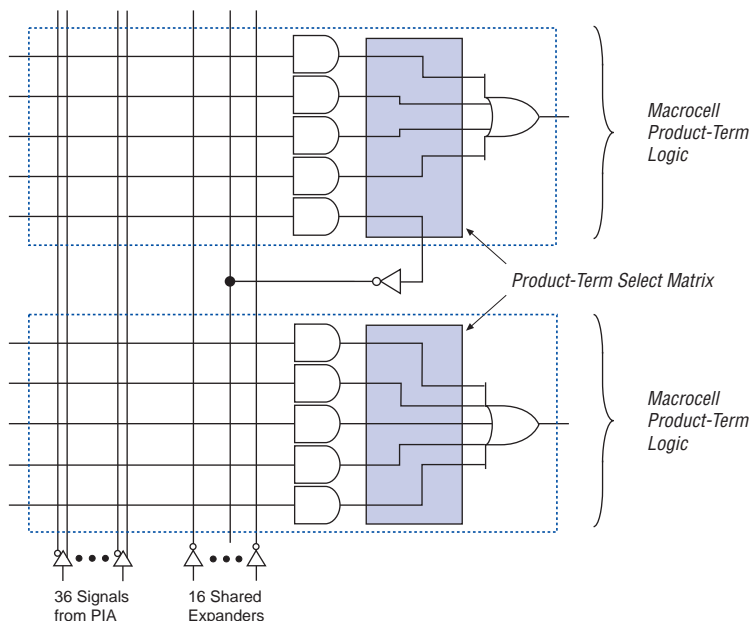
Although most logic functions can be implemented with the five product terms available in each macrocell, more complex logic functions require additional product terms. Another macrocell can be used to supply the required logic resources. However, the MAX 7000A architecture also offers both shareable and parallel expander product terms that provide additional product terms directly to any macrocell in the same LAB. These expanders help ensure that logic is synthesized with the fewest possible logic resources to obtain the fastest possible speed.

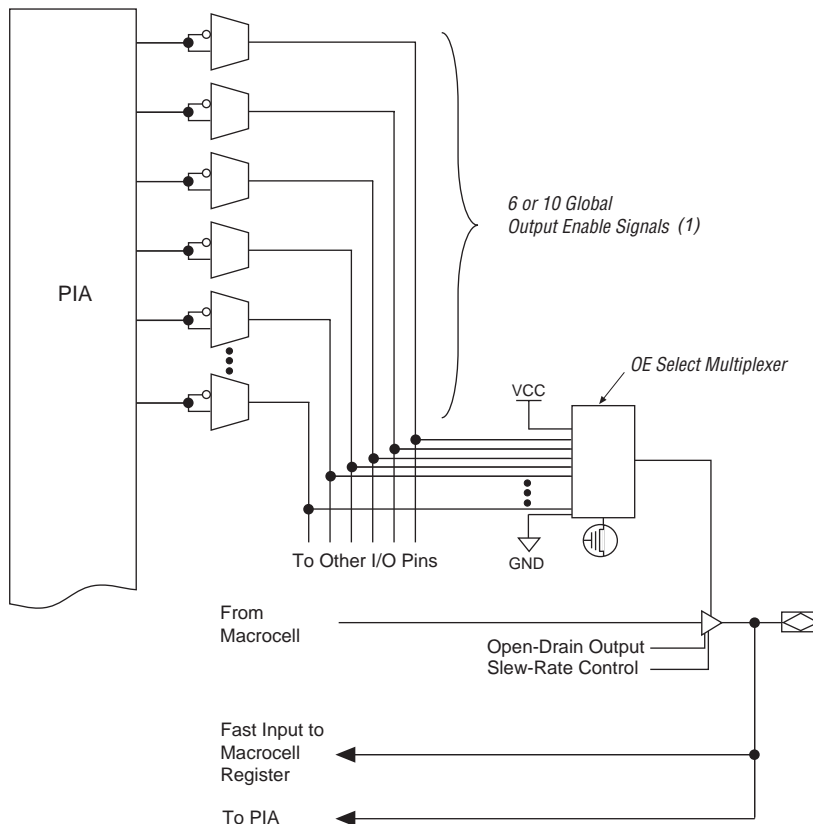
### Shareable Expanders

Each LAB has 16 shareable expanders that can be viewed as a pool of uncommitted single product terms (one from each macrocell) with inverted outputs that feed back into the logic array. Each shareable expander can be used and shared by any or all macrocells in the LAB to build complex logic functions. A small delay ( $t_{SEXP}$ ) is incurred when shareable expanders are used. Figure 3 shows how shareable expanders can feed multiple macrocells.

**Figure 3. MAX 7000A Shareable Expanders**

*Shareable expanders can be shared by any or all macrocells in an LAB.*



**Figure 6. I/O Control Block of MAX 7000A Devices****Note:**

- (1) EPM7032AE, EPM7064AE, EPM7128A, EPM7128AE, EPM7256A, and EPM7256AE devices have six output enable signals. EPM7512AE devices have 10 output enable signals.

When the tri-state buffer control is connected to ground, the output is tri-stated (high impedance) and the I/O pin can be used as a dedicated input. When the tri-state buffer control is connected to  $V_{CC}$ , the output is enabled.

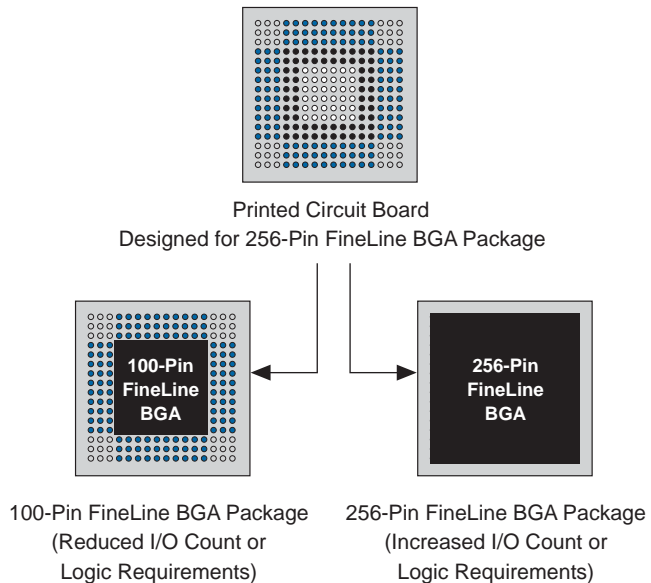
The MAX 7000A architecture provides dual I/O feedback, in which macrocell and pin feedbacks are independent. When an I/O pin is configured as an input, the associated macrocell can be used for buried logic.

## SameFrame Pin-Outs

MAX 7000A devices support the SameFrame pin-out feature for FineLine BGA packages. The SameFrame pin-out feature is the arrangement of balls on FineLine BGA packages such that the lower-ball-count packages form a subset of the higher-ball-count packages. SameFrame pin-outs provide the flexibility to migrate not only from device to device within the same package, but also from one package to another. A given printed circuit board (PCB) layout can support multiple device density/package combinations. For example, a single board layout can support a range of devices from an EPM7128AE device in a 100-pin FineLine BGA package to an EPM7512AE device in a 256-pin FineLine BGA package.

The Altera design software provides support to design PCBs with SameFrame pin-out devices. Devices can be defined for present and future use. The software generates pin-outs describing how to lay out a board to take advantage of this migration (see [Figure 7](#)).

**Figure 7. SameFrame Pin-Out Example**



**Table 8. MAX 7000A JTAG Instructions**

JTAG Instruction	Description
SAMPLE/PRELOAD	Allows a snapshot of signals at the device pins to be captured and examined during normal device operation, and permits an initial data pattern output at the device pins
EXTEST	Allows the external circuitry and board-level interconnections to be tested by forcing a test pattern at the output pins and capturing test results at the input pins
BYPASS	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through a selected device to adjacent devices during normal device operation
IDCODE	Selects the IDCODE register and places it between the TDI and TDO pins, allowing the IDCODE to be serially shifted out of TDO
USERCODE	Selects the 32-bit USERCODE register and places it between the TDI and TDO pins, allowing the USERCODE value to be shifted out of TDO. The USERCODE instruction is available for MAX 7000AE devices only
UESCODE	These instructions select the user electronic signature (UESCODE) and allow the UESCODE to be shifted out of TDO. UESCODE instructions are available for EPM7128A and EPM7256A devices only.
ISP Instructions	These instructions are used when programming MAX 7000A devices via the JTAG ports with the MasterBlaster, ByteBlasterMV, or BitBlaster download cable, or using a Jam STAPL File, JBC File, or SVF File via an embedded processor or test equipment.



Figure 8 shows timing information for the JTAG signals.

**Figure 8. MAX 7000A JTAG Waveforms**

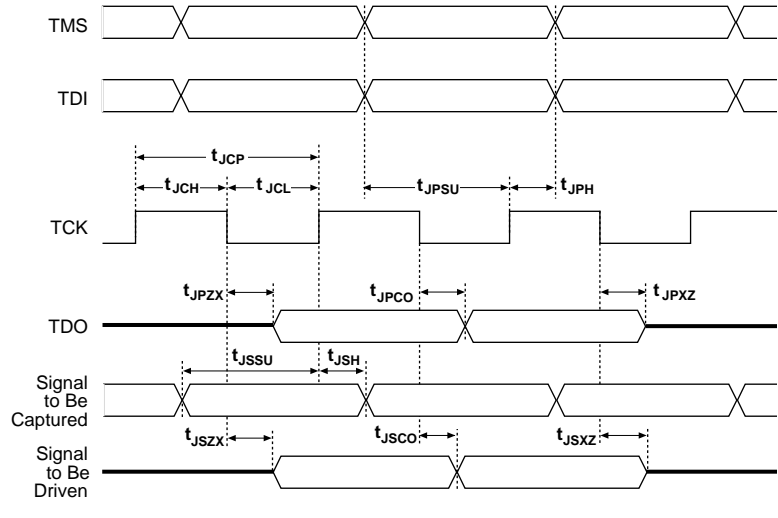


Table 11 shows the JTAG timing parameters and values for MAX 7000A devices.

**Table 11. JTAG Timing Parameters & Values for MAX 7000A Devices** *Note (1)*

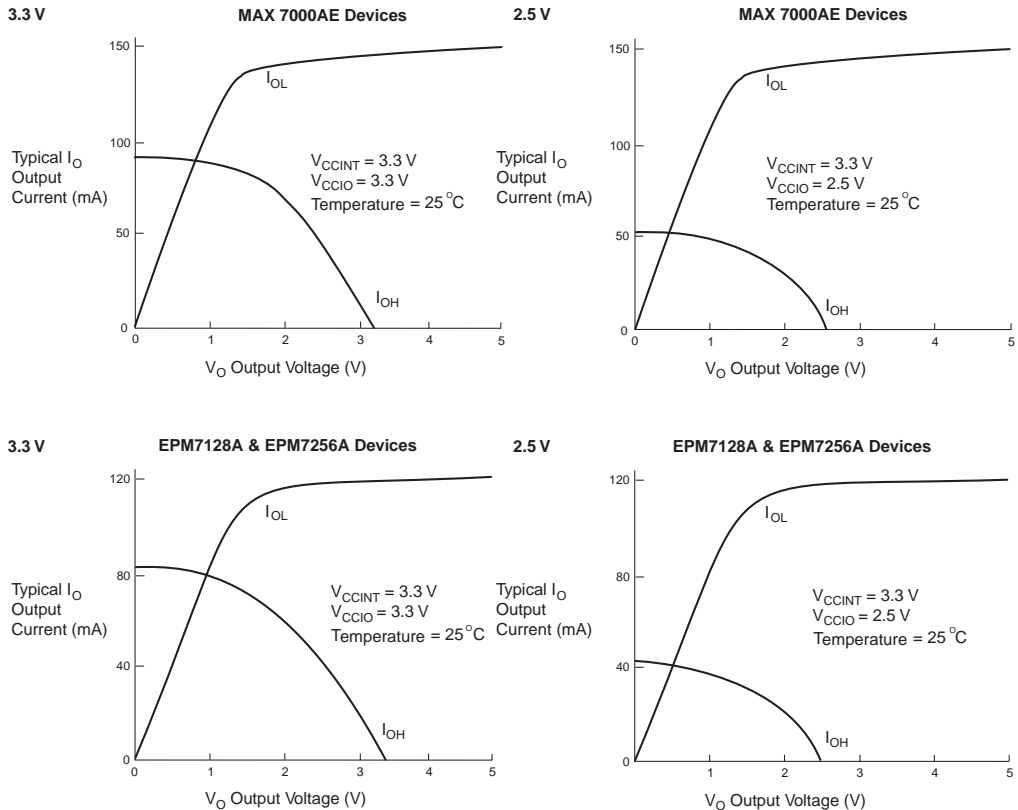
Symbol	Parameter	Min	Max	Unit
$t_{JCP}$	TCK clock period	100		ns
$t_{JCH}$	TCK clock high time	50		ns
$t_{JCL}$	TCK clock low time	50		ns
$t_{JPSU}$	JTAG port setup time	20		ns
$t_{JPH}$	JTAG port hold time	45		ns
$t_{JPCO}$	JTAG port clock to output		25	ns
$t_{JPZX}$	JTAG port high impedance to valid output		25	ns
$t_{JPXZ}$	JTAG port valid output to high impedance		25	ns
$t_{JSSU}$	Capture register setup time	20		ns
$t_{JSH}$	Capture register hold time	45		ns
$t_{JSCO}$	Update register clock to output		25	ns
$t_{JSZX}$	Update register high impedance to valid output		25	ns
$t_{JSXZ}$	Update register valid output to high impedance		25	ns

**Note:**

(1) Timing parameters shown in this table apply for all specified VCCIO levels.

Figure 10 shows the typical output drive characteristics of MAX 7000A devices.

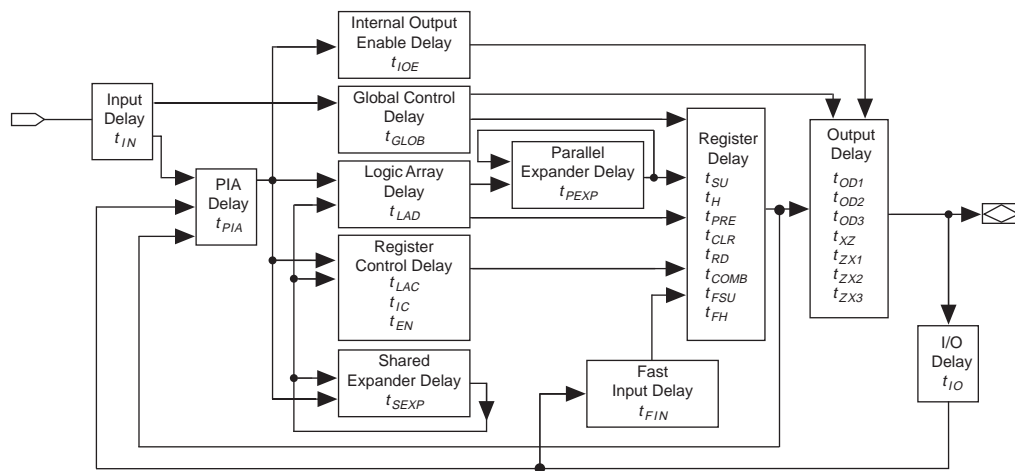
**Figure 10. Output Drive Characteristics of MAX 7000A Devices**



## Timing Model

MAX 7000A device timing can be analyzed with the Altera software, a variety of popular industry-standard EDA simulators and timing analyzers, or with the timing model shown in Figure 11. MAX 7000A devices have predictable internal delays that enable the designer to determine the worst-case timing of any design. The software provides timing simulation, point-to-point delay prediction, and detailed timing analysis for device-wide performance evaluation.

**Figure 11. MAX 7000A Timing Model**



The timing characteristics of any signal path can be derived from the timing model and parameters of a particular device. External timing parameters, which represent pin-to-pin timing delays, can be calculated as the sum of internal parameters. [Figure 12](#) shows the timing relationship between internal and external delay parameters.



See *Application Note 94 (Understanding MAX 7000 Timing)* for more information.

Tables 17 through 30 show EPM7032AE, EPM7064AE, EPM7128AE, EPM7256AE, EPM7512AE, EPM7128A, and EPM7256A timing information.

**Table 17. EPM7032AE External Timing Parameters** *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-4		-7		-10		
			Min	Max	Min	Max	Min	Max	
t <sub>PD1</sub>	Input to non-registered output	C1 = 35 pF (2)		4.5		7.5		10	ns
t <sub>PD2</sub>	I/O input to non-registered output	C1 = 35 pF (2)		4.5		7.5		10	ns
t <sub>SU</sub>	Global clock setup time	(2)	2.9		4.7		6.3		ns
t <sub>H</sub>	Global clock hold time	(2)	0.0		0.0		0.0		ns
t <sub>FSU</sub>	Global clock setup time of fast input		2.5		3.0		3.0		ns
t <sub>FH</sub>	Global clock hold time of fast input		0.0		0.0		0.0		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF	1.0	3.0	1.0	5.0	1.0	6.7	ns
t <sub>CH</sub>	Global clock high time		2.0		3.0		4.0		ns
t <sub>CL</sub>	Global clock low time		2.0		3.0		4.0		ns
t <sub>ASU</sub>	Array clock setup time	(2)	1.6		2.5		3.6		ns
t <sub>AH</sub>	Array clock hold time	(2)	0.3		0.5		0.5		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF (2)	1.0	4.3	1.0	7.2	1.0	9.4	ns
t <sub>ACH</sub>	Array clock high time		2.0		3.0		4.0		ns
t <sub>ACL</sub>	Array clock low time		2.0		3.0		4.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(3)	2.0		3.0		4.0		ns
t <sub>CNT</sub>	Minimum global clock period	(2)		4.4		7.2		9.7	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(2), (4)	227.3		138.9		103.1		MHz
t <sub>ACNT</sub>	Minimum array clock period	(2)		4.4		7.2		9.7	ns
f <sub>ACNT</sub>	Maximum internal array clock frequency	(2), (4)	227.3		138.9		103.1		MHz

**Table 20. EPM7064AE Internal Timing Parameters (Part 1 of 2)** *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-4		-7		-10		
			Min	Max	Min	Max	Min	Max	
$t_{IN}$	Input pad and buffer delay			0.6		1.1		1.4	ns
$t_{IO}$	I/O input pad and buffer delay			0.6		1.1		1.4	ns
$t_{FIN}$	Fast input delay			2.5		3.0		3.7	ns
$t_{SEXP}$	Shared expander delay			1.8		3.0		3.9	ns
$t_{PEXP}$	Parallel expander delay			0.4		0.7		0.9	ns
$t_{LAD}$	Logic array delay			1.5		2.5		3.2	ns
$t_{LAC}$	Logic control array delay			0.6		1.0		1.2	ns
$t_{IOE}$	Internal output enable delay			0.0		0.0		0.0	ns
$t_{OD1}$	Output buffer and pad delay, slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		0.8		1.3		1.8	ns
$t_{OD2}$	Output buffer and pad delay, slow slew rate = off $V_{CCIO} = 2.5\text{ V}$	$C1 = 35\text{ pF}$ (5)		1.3		1.8		2.3	ns
$t_{OD3}$	Output buffer and pad delay, slow slew rate = on $V_{CCIO} = 2.5\text{ V}$ or $3.3\text{ V}$	$C1 = 35\text{ pF}$		5.8		6.3		6.8	ns
$t_{ZX1}$	Output buffer enable delay, slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		4.0		4.0		5.0	ns
$t_{ZX2}$	Output buffer enable delay, slow slew rate = off $V_{CCIO} = 2.5\text{ V}$	$C1 = 35\text{ pF}$ (5)		4.5		4.5		5.5	ns
$t_{ZX3}$	Output buffer enable delay, slow slew rate = on $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		9.0		9.0		10.0	ns
$t_{XZ}$	Output buffer disable delay	$C1 = 5\text{ pF}$		4.0		4.0		5.0	ns
$t_{SU}$	Register setup time		1.3		2.0		2.9		ns
$t_H$	Register hold time		0.6		1.0		1.3		ns
$t_{FSU}$	Register setup time of fast input		1.0		1.5		1.5		ns
$t_{FH}$	Register hold time of fast input		1.5		1.5		1.5		ns
$t_{RD}$	Register delay			0.7		1.2		1.6	ns
$t_{COMB}$	Combinatorial delay			0.6		0.9		1.3	ns
$t_{IC}$	Array clock delay			1.2		1.9		2.5	ns

**Table 21. EPM7128AE External Timing Parameters** *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-5		-7		-10		
			Min	Max	Min	Max	Min	Max	
t <sub>PD1</sub>	Input to non-registered output	C1 = 35 pF (2)		5.0		7.5		10	ns
t <sub>PD2</sub>	I/O input to non-registered output	C1 = 35 pF (2)		5.0		7.5		10	ns
t <sub>SU</sub>	Global clock setup time	(2)	3.3		4.9		6.6		ns
t <sub>H</sub>	Global clock hold time	(2)	0.0		0.0		0.0		ns
t <sub>FSU</sub>	Global clock setup time of fast input		2.5		3.0		3.0		ns
t <sub>FH</sub>	Global clock hold time of fast input		0.0		0.0		0.0		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF	1.0	3.4	1.0	5.0	1.0	6.6	ns
t <sub>CH</sub>	Global clock high time		2.0		3.0		4.0		ns
t <sub>CL</sub>	Global clock low time		2.0		3.0		4.0		ns
t <sub>ASU</sub>	Array clock setup time	(2)	1.8		2.8		3.8		ns
t <sub>AH</sub>	Array clock hold time	(2)	0.2		0.3		0.4		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF (2)	1.0	4.9	1.0	7.1	1.0	9.4	ns
t <sub>ACH</sub>	Array clock high time		2.0		3.0		4.0		ns
t <sub>ACL</sub>	Array clock low time		2.0		3.0		4.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(3)	2.0		3.0		4.0		ns
t <sub>CNT</sub>	Minimum global clock period	(2)		5.2		7.7		10.2	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(2), (4)	192.3		129.9		98.0		MHz
t <sub>ACNT</sub>	Minimum array clock period	(2)		5.2		7.7		10.2	ns
f <sub>ACNT</sub>	Maximum internal array clock frequency	(2), (4)	192.3		129.9		98.0		MHz

**Table 22. EPM7128AE Internal Timing Parameters (Part 2 of 2)** *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-5		-7		-10		
			Min	Max	Min	Max	Min	Max	
$t_{EN}$	Register enable time			0.7		1.0		1.3	ns
$t_{GLOB}$	Global control delay			1.1		1.6		2.0	ns
$t_{PRE}$	Register preset time			1.4		2.0		2.7	ns
$t_{CLR}$	Register clear time			1.4		2.0		2.7	ns
$t_{PIA}$	PIA delay	(2)		1.4		2.0		2.6	ns
$t_{LPA}$	Low-power adder	(6)		4.0		4.0		5.0	ns

**Table 23. EPM7256AE External Timing Parameters** *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-5		-7		-10		
			Min	Max	Min	Max	Min	Max	
t <sub>PD1</sub>	Input to non-registered output	C1 = 35 pF (2)		5.5		7.5		10	ns
t <sub>PD2</sub>	I/O input to non-registered output	C1 = 35 pF (2)		5.5		7.5		10	ns
t <sub>SU</sub>	Global clock setup time	(2)	3.9		5.2		6.9		ns
t <sub>H</sub>	Global clock hold time	(2)	0.0		0.0		0.0		ns
t <sub>FSU</sub>	Global clock setup time of fast input		2.5		3.0		3.0		ns
t <sub>FH</sub>	Global clock hold time of fast input		0.0		0.0		0.0		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF	1.0	3.5	1.0	4.8	1.0	6.4	ns
t <sub>CH</sub>	Global clock high time		2.0		3.0		4.0		ns
t <sub>CL</sub>	Global clock low time		2.0		3.0		4.0		ns
t <sub>ASU</sub>	Array clock setup time	(2)	2.0		2.7		3.6		ns
t <sub>AH</sub>	Array clock hold time	(2)	0.2		0.3		0.5		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF (2)	1.0	5.4	1.0	7.3	1.0	9.7	ns
t <sub>ACH</sub>	Array clock high time		2.0		3.0		4.0		ns
t <sub>ACL</sub>	Array clock low time		2.0		3.0		4.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(3)	2.0		3.0		4.0		ns
t <sub>CNT</sub>	Minimum global clock period	(2)		5.8		7.9		10.5	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(2), (4)	172.4		126.6		95.2		MHz
t <sub>ACNT</sub>	Minimum array clock period	(2)		5.8		7.9		10.5	ns
f <sub>ACNT</sub>	Maximum internal array clock frequency	(2), (4)	172.4		126.6		95.2		MHz



Table 27. EPM7128A External Timing Parameters

Note (1)

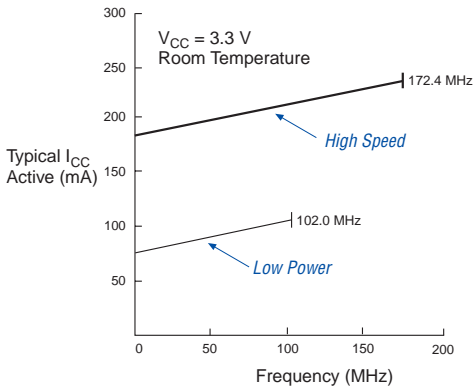
Symbol	Parameter	Conditions	Speed Grade								Unit
			-6		-7		-10		-12		
			Min	Max	Min	Max	Min	Max	Min	Max	
t <sub>PD1</sub>	Input to non-registered output	C1 = 35 pF (2)		6.0		7.5		10.0		12.0	ns
t <sub>PD2</sub>	I/O input to non-registered output	C1 = 35 pF (2)		6.0		7.5		10.0		12.0	ns
t <sub>SU</sub>	Global clock setup time	(2)	4.2		5.3		7.0		8.5		ns
t <sub>H</sub>	Global clock hold time	(2)	0.0		0.0		0.0		0.0		ns
t <sub>FSU</sub>	Global clock setup time of fast input		2.5		3.0		3.0		3.0		ns
t <sub>FH</sub>	Global clock hold time of fast input		0.0		0.0		0.0		0.0		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF	1.0	3.7	1.0	4.6	1.0	6.1	1.0	7.3	ns
t <sub>CH</sub>	Global clock high time		3.0		3.0		4.0		5.0		ns
t <sub>CL</sub>	Global clock low time		3.0		3.0		4.0		5.0		ns
t <sub>ASU</sub>	Array clock setup time	(2)	1.9		2.4		3.1		3.8		ns
t <sub>AH</sub>	Array clock hold time	(2)	1.5		2.2		3.3		4.3		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF (2)	1.0	6.0	1.0	7.5	1.0	10.0	1.0	12.0	ns
t <sub>ACH</sub>	Array clock high time		3.0		3.0		4.0		5.0		ns
t <sub>ACL</sub>	Array clock low time		3.0		3.0		4.0		5.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(3)	3.0		3.0		4.0		5.0		ns
t <sub>CNT</sub>	Minimum global clock period	(2)		6.9		8.6		11.5		13.8	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(2), (4)	144.9		116.3		87.0		72.5		MHz
t <sub>ACNT</sub>	Minimum array clock period	(2)		6.9		8.6		11.5		13.8	ns
f <sub>ACNT</sub>	Maximum internal array clock frequency	(2), (4)	144.9		116.3		87		72.5		MHz

**Table 30. EPM7256A Internal Timing Parameters (Part 1 of 2)** *Note (1)*

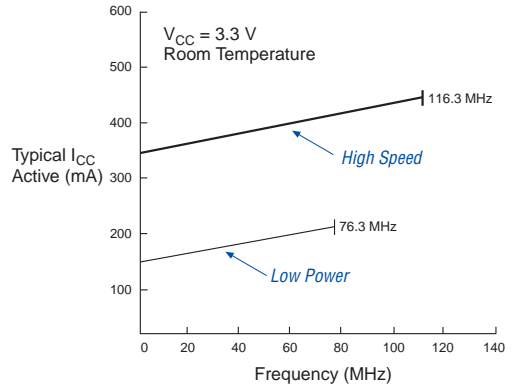
Symbol	Parameter	Conditions	Speed Grade								Unit
			-6		-7		-10		-12		
			Min	Max	Min	Max	Min	Max	Min	Max	
$t_{IN}$	Input pad and buffer delay			0.3		0.4		0.5		0.6	ns
$t_{IO}$	I/O input pad and buffer delay			0.3		0.4		0.5		0.6	ns
$t_{FIN}$	Fast input delay			2.4		3.0		3.4		3.8	ns
$t_{SEXP}$	Shared expander delay			2.8		3.5		4.7		5.6	ns
$t_{PEXP}$	Parallel expander delay			0.5		0.6		0.8		1.0	ns
$t_{LAD}$	Logic array delay			2.5		3.1		4.2		5.0	ns
$t_{LAC}$	Logic control array delay			2.5		3.1		4.2		5.0	ns
$t_{IOE}$	Internal output enable delay			0.2		0.3		0.4		0.5	ns
$t_{OD1}$	Output buffer and pad delay, slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		0.3		0.4		0.5		0.6	ns
$t_{OD2}$	Output buffer and pad delay, slow slew rate = off $V_{CCIO} = 2.5\text{ V}$	$C1 = 35\text{ pF}$ (5)		0.8		0.9		1.0		1.1	ns
$t_{OD3}$	Output buffer and pad delay slow slew rate = on $V_{CCIO} = 2.5\text{ V}$ or $3.3\text{ V}$	$C1 = 35\text{ pF}$		5.3		5.4		5.5		5.6	ns
$t_{ZX1}$	Output buffer enable delay slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		4.0		4.0		5.0		5.0	ns
$t_{ZX2}$	Output buffer enable delay slow slew rate = off $V_{CCIO} = 2.5\text{ V}$	$C1 = 35\text{ pF}$ (5)		4.5		4.5		5.5		5.5	ns
$t_{ZX3}$	Output buffer enable delay slow slew rate = on $V_{CCIO} = 2.5\text{ V}$ or $3.3\text{ V}$	$C1 = 35\text{ pF}$		9.0		9.0		10.0		10.0	ns
$t_{XZ}$	Output buffer disable delay	$C1 = 5\text{ pF}$		4.0		4.0		5.0		5.0	ns
$t_{SU}$	Register setup time		1.0		1.3		1.7		2.0		ns
$t_H$	Register hold time		1.7		2.4		3.7		4.7		ns
$t_{FSU}$	Register setup time of fast input		1.2		1.4		1.4		1.4		ns
$t_{FH}$	Register hold time of fast input		1.3		1.6		1.6		1.6		ns
$t_{RD}$	Register delay			1.6		2.0		2.7		3.2	ns

Figure 13.  $I_{CC}$  vs. Frequency for MAX 7000A Devices (Part 2 of 2)

EPM7256A & EPM7256AE



EPM7512AE



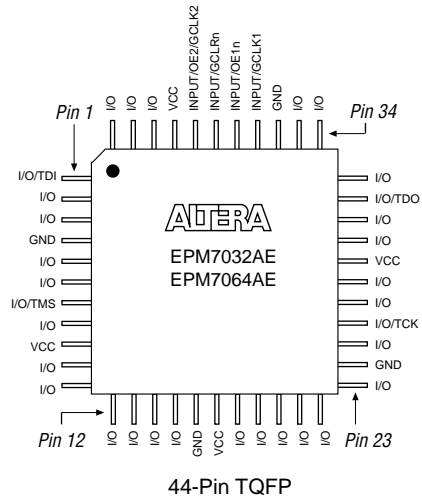
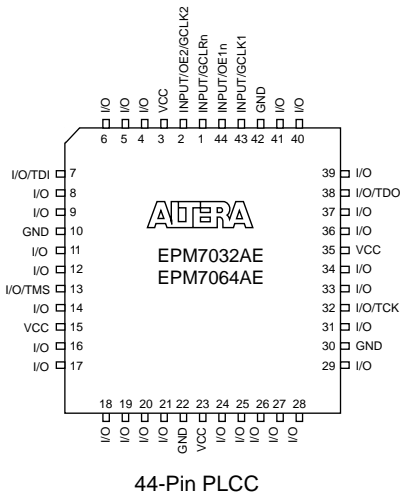
## Device Pin-Outs

See the Altera web site (<http://www.altera.com>) or the *Altera Digital Library* for pin-out information.

Figures 14 through 23 show the package pin-out diagrams for MAX 7000A devices.

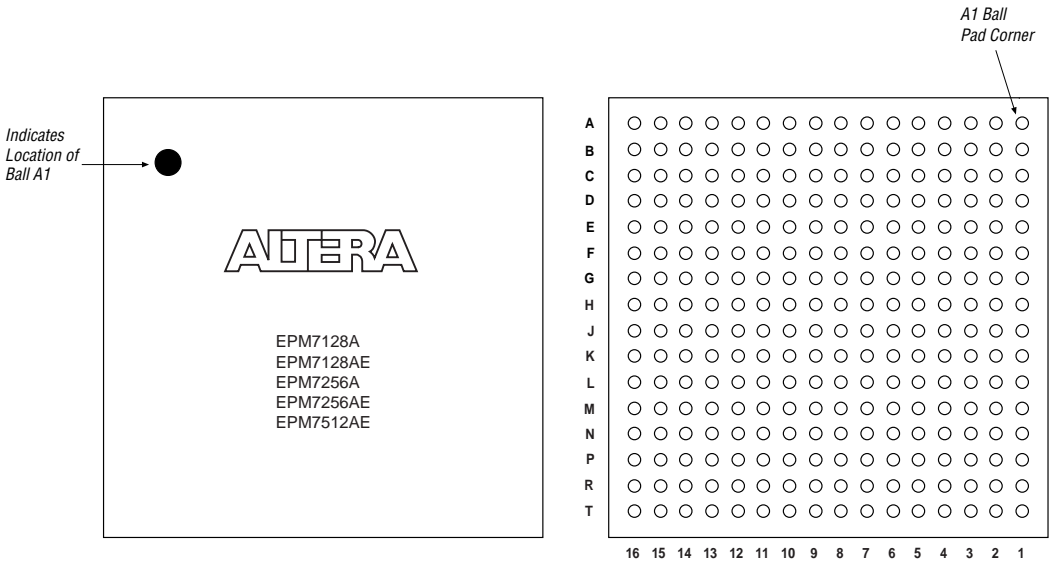
Figure 14. 44-Pin PLCC/TQFP Package Pin-Out Diagram

Package outlines not drawn to scale.



**Figure 23. 256-Pin FineLine BGA Package Pin-Out Diagram**

Package outline not drawn to scale.



## Revision History

The information contained in the *MAX 7000A Programmable Logic Device Data Sheet* version 4.5 supersedes information published in previous versions.

### Version 4.5

The following changes were made in the *MAX 7000A Programmable Logic Device Data Sheet* version 4.5:

- Updated text in the “Power Sequencing & Hot-Socketing” section.

### Version 4.4

The following changes were made in the *MAX 7000A Programmable Logic Device Data Sheet* version 4.4:

- Added Tables 5 through 7.
- Added “Programming Sequence” on page 17 and “Programming Times” on page 18.

## Version 4.3

The following changes were made in the *MAX 7000A Programmable Logic Device Data Sheet* version 4.3:

- Added extended temperature devices to document
- Updated [Table 14](#).

## Version 4.2

The following changes were made in the *MAX 7000A Programmable Logic Device Data Sheet* version 4.2:

- Removed *Note (1)* from [Table 2](#).
- Removed *Note (4)* from [Tables 3](#) and [4](#).

## Version 4.1

The following changes were made in the *MAX 7000A Programmable Logic Device Data Sheet* version 4.1:

- Updated leakage current information in [Table 15](#).
- Updated [Note \(9\)](#) of [Table 15](#).
- Updated [Note \(1\)](#) of [Tables 17](#) through [30](#).



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